

Electronic Supplementary Information

CuGaS₂ nanoplates: a robust and self-healing anode for power battery in wide temperaturerange of 268-318 K

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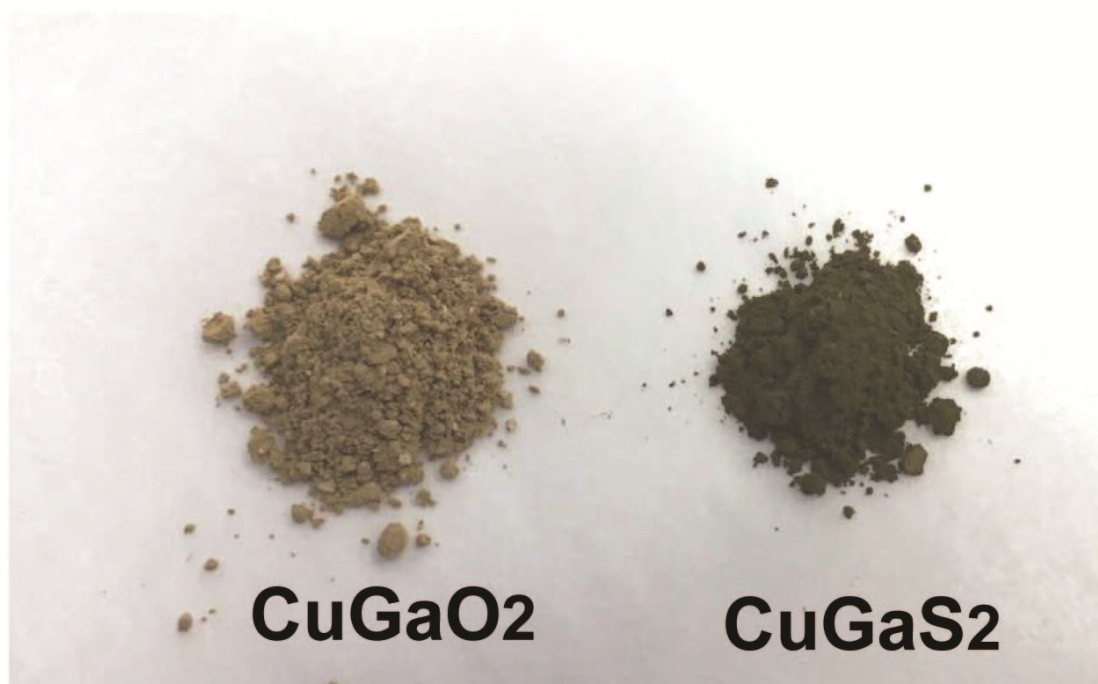


Figure S1. The distinct color of CuGaO_2 (brown) and CuGaS_2 (dark green) power.

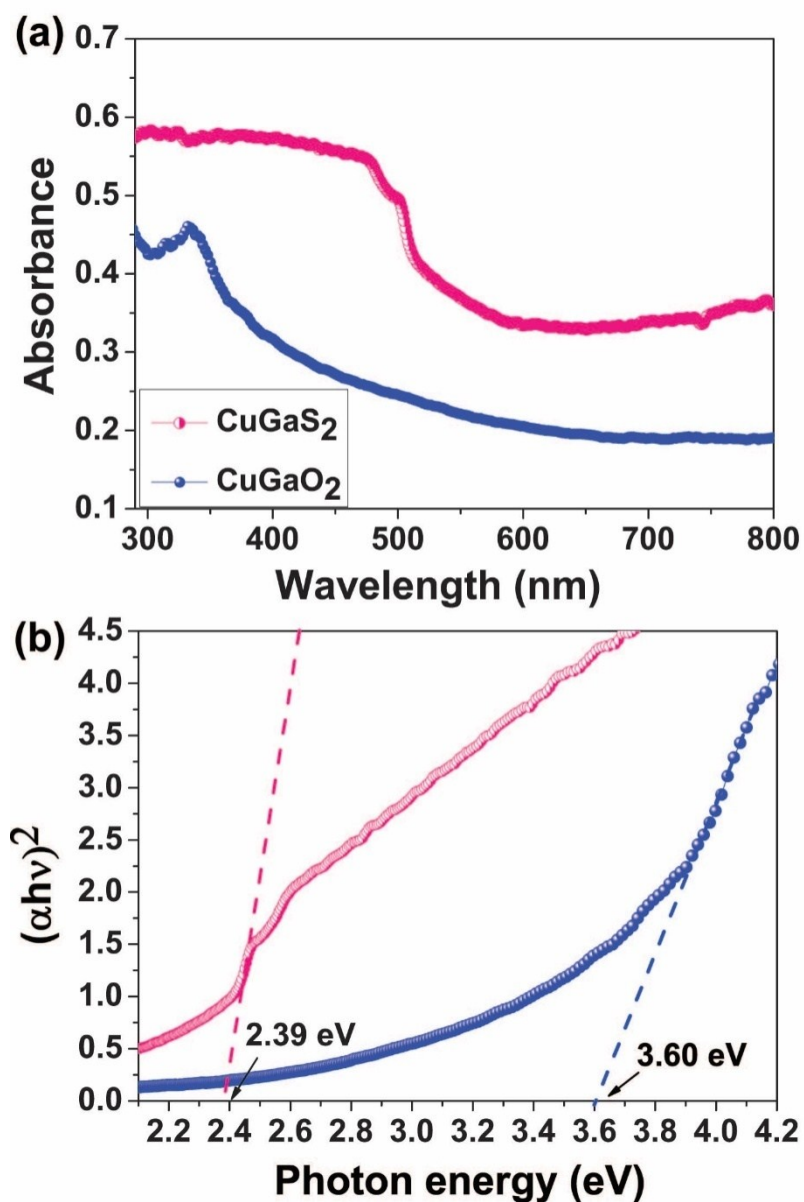


Figure. S2. (a) UV-vis absorption spectra of the CuGaS₂ hexagonal nanoplates and CuGaO₂ precursor, respectively. (b) The corresponding plot analysis of the optical band gap of CuGaS₂ and CuGaO₂, respectively.

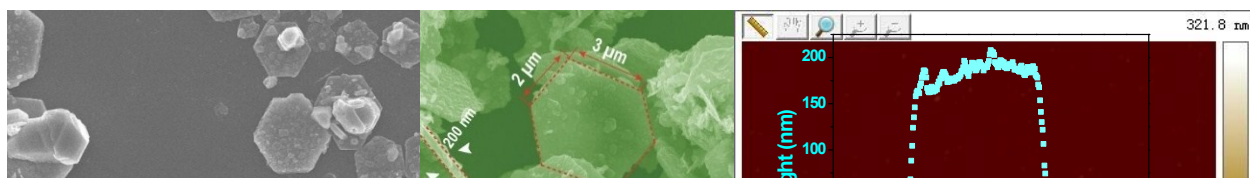


Figure S3. Typical SEM image and AFM image of CuGaS₂ hexagonal nanoplates.

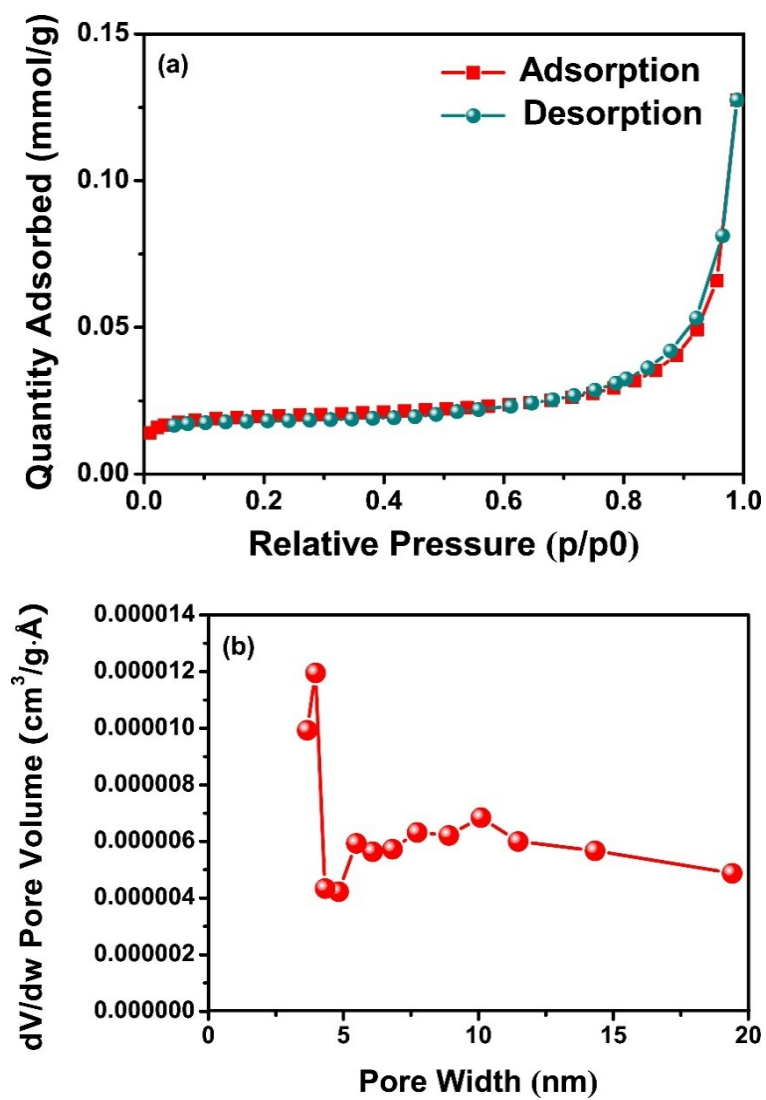


Figure. S4. (a) Nitrogen adsorption–desorption isotherms and (b) pore size distribution of the as-transformed CuGaS₂ nanoplates.

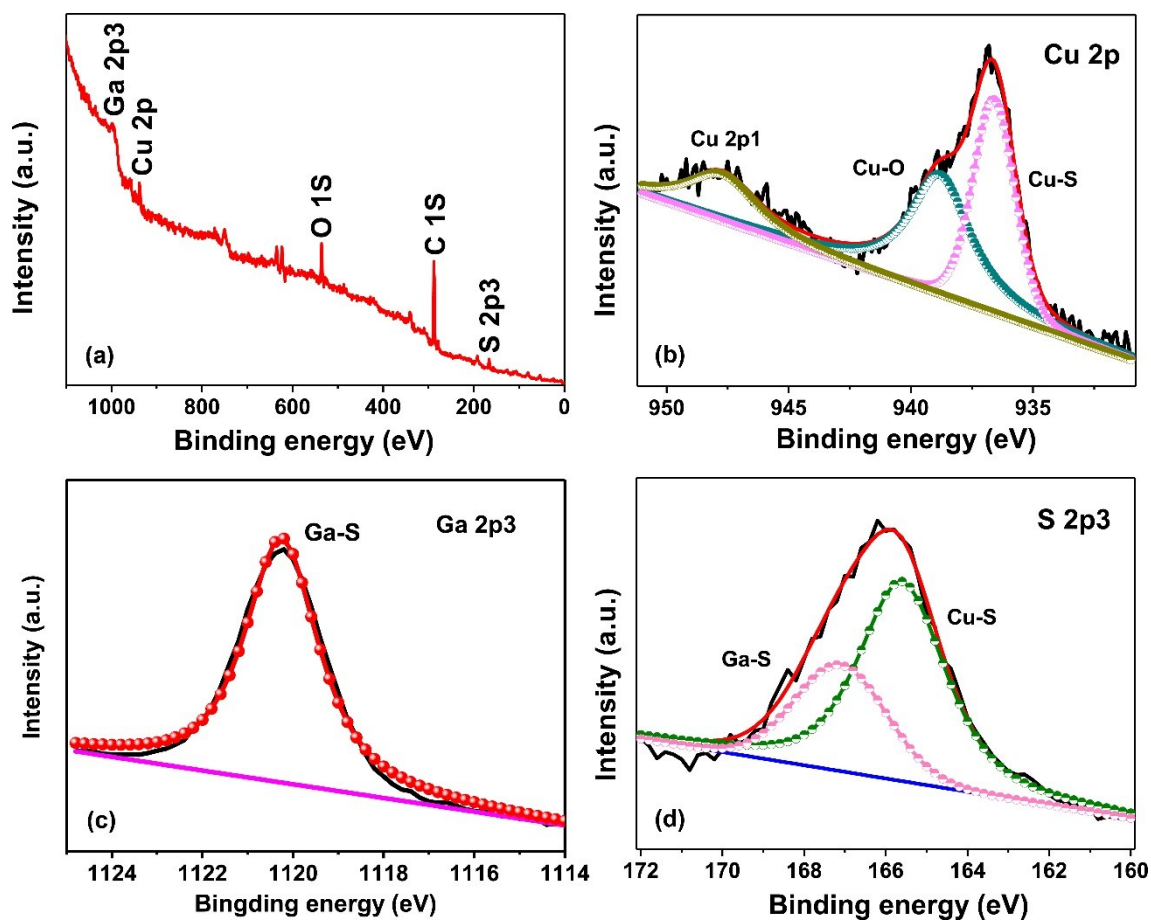


Figure S5. XPS survey spectra and high-resolution XPS spectra of (b) Cu 2p, (c) Ga 2p₃ and (d) S 2p₃ for our CuGaS₂ nanoplates. The full-scan spectra in (a) show the presence of the Cu 2p, Ga 2p and S 2p peaks. The Cu 2p, Ga 2p and S 2p core levels were scanned respectively. As presented in (b), the fitting of Cu 2p spectra disclosed the presence of Cu-S, Cu-OH peaks. The corresponding S 2p₃ spectrum of the sample (d) displays three main peaks at 163.1 and 161.5 eV for Ga-S, and Cu-S bonds, respectively.

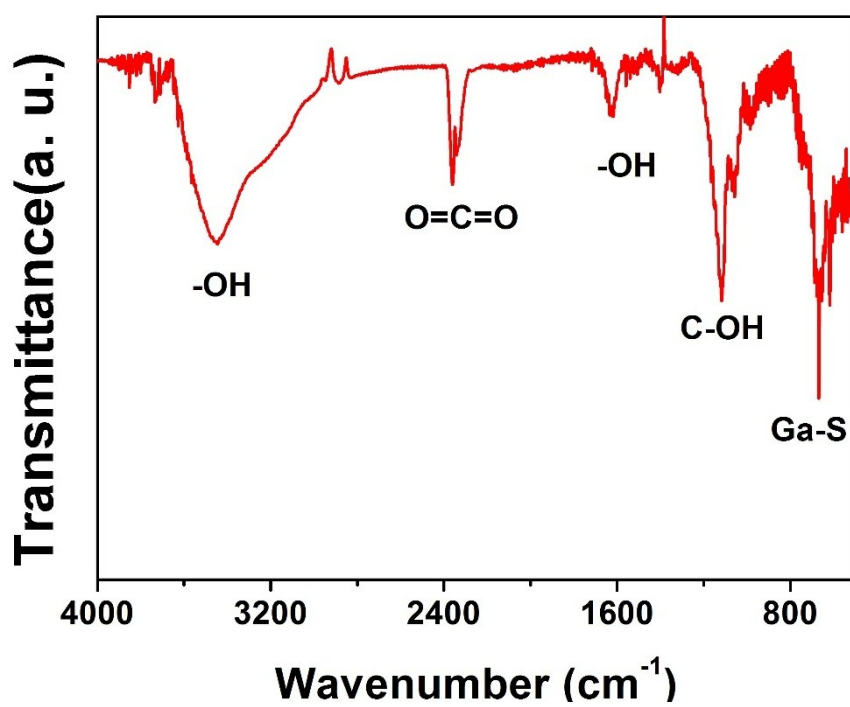


Figure S6. FTIR spectrum for CuGaS₂ nanoplates. The large band centered at 3500 cm⁻¹ is assigned to the O-H stretching modes of adsorbed water molecules on the sample surface.

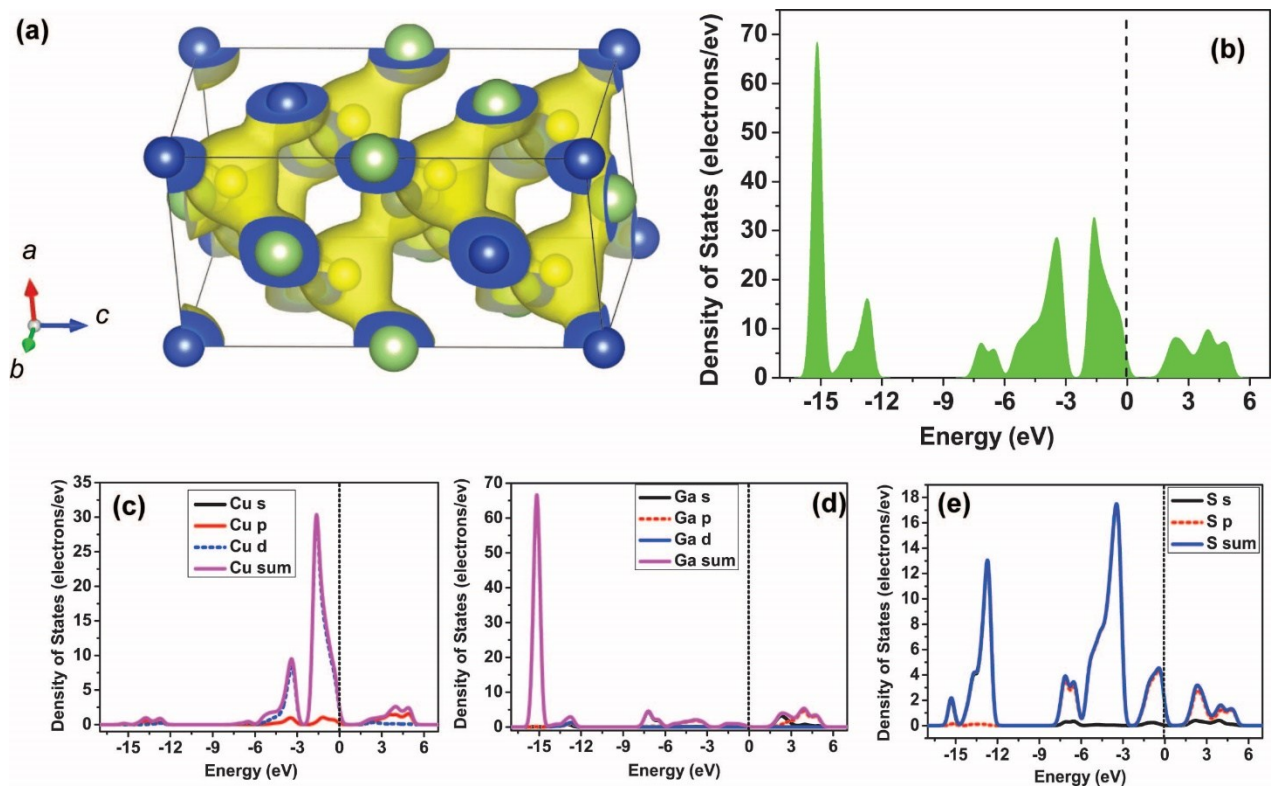


Figure S7. Density function theory calculation studies of CuGaS₂. (a) 3D charge density distribution of a CuGaS₂ unit cell. Blue and yellow regions represent charge accumulation and depletion, respectively. (b) Calculated total density of states (DOS). The projected density of states (PDOS) of (c) Cu s, p, d (d) Ga s, p, d, (e) S s, p orbitals. DFT is hampered by two important shortcomings when applied in this context: (i) the Kohn-Sham (KS) band gap is systematically underestimated by 50% to 100% compared to photoemission experiments; and (ii) there is deficient cancellation of the spurious self-interaction terms in standard functionals, particularly critical for d electrons, which are usually located too high in energy. For systems with shallow d states, like the chalcopyrites, this has a direct effect on the band gap.

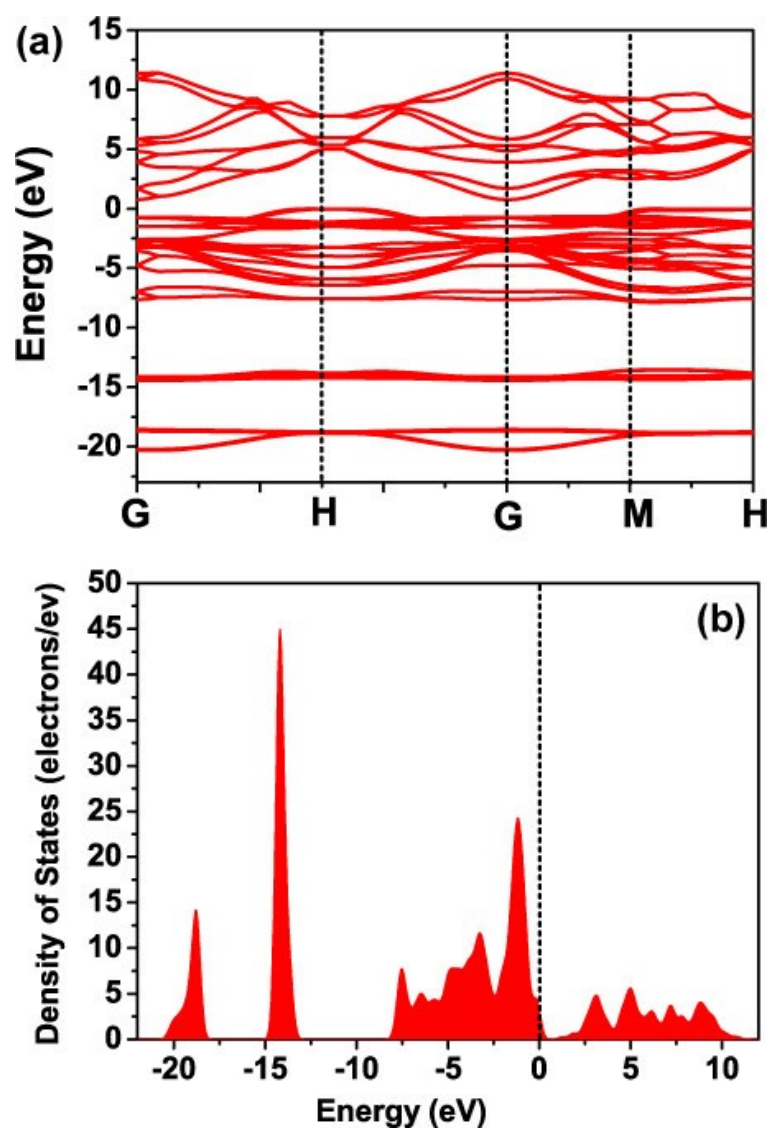


Figure S8. Calculated band structure and (d) total density of states (DOS) of CuGaO₂ precursor.

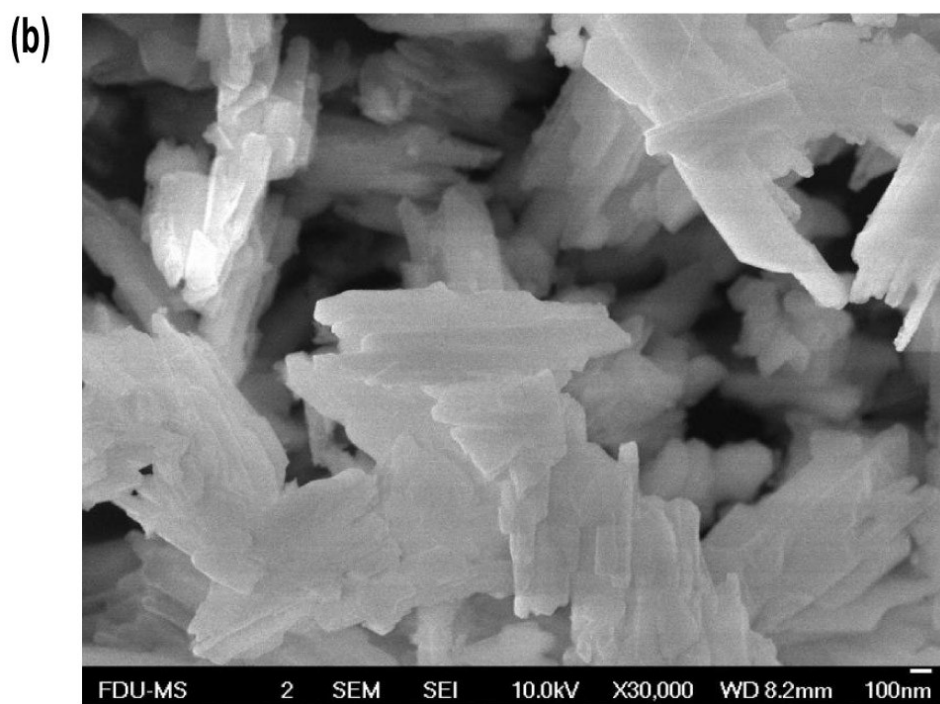
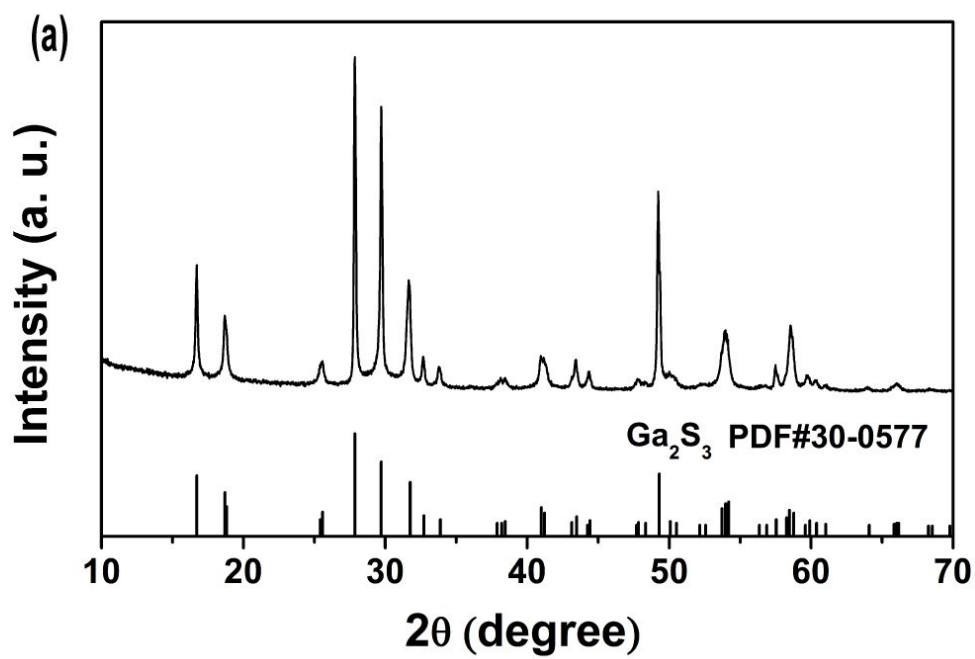


Figure S10. (a) XRD pattern (b) typical SEM image of Ga_2S_3 powder.

Table S1. Comparison of the characteristic parameters of different Ga-based electrodes for LIBs applications.

Electrodes	Current Density	Cycling Number	Specific Capacity/ Temperature	Reference
Ga ₂ S ₃	0.1 A g ⁻¹	20	400 mAh g ⁻¹ @ R.T.	1
Ga ₂ Se ₃	0.1 C	100	600 mAh g ⁻¹ @ R.T.	2
GaSe	1 A g ⁻¹	100	600 mAh g ⁻¹ @ R.T.	3
	5 A g ⁻¹	—	450 mAh g ⁻¹ @ R.T.	
GaS _x	0.6 A g ⁻¹	100	600 mAh g ⁻¹ @ R.T.	4
Ga ₂ O ₃	0.05 A g ⁻¹	40	800 mAh g ⁻¹ @ R.T.	5
CuGaS₂	5 A g⁻¹	600	521 mAh g⁻¹ @ R.T.	This work
CuGaS₂	0.5 A g⁻¹	80	784 mAh g⁻¹ @318 K	This work
CuGaS₂	0.5 A g⁻¹	80	407 mAh g⁻¹ @ 268 K	This work

Table S2. Comparison of the characteristic parameters of different electrodes for NIBs applications.

Electrodes	Current Density	Cycling Number	Specific Capacity	Reference
CoS ₂ @MWNT	0.1 A g ⁻¹	100	568 mAh g ⁻¹	6
MoS ₂ @MWNT	0.05 A g ⁻¹	100	504 mAh g ⁻¹	7
SnO ₂ @Al ₂ O ₃	0.134 A g ⁻¹	100	375 mAh g ⁻¹	8
MoS ₂ @graphen e	0.02 A g ⁻¹	100	344 mAh g ⁻¹	9
FeS@Carbon	0.5 A g ⁻¹	200	280	10
CuS@graphene	1 A g ⁻¹	450	345 mAh g ⁻¹	11
CuGaS₂	1 A g⁻¹	100	321 mAh g⁻¹	This work

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